

1. Record Nr.	UNINA9910151738903321
Titolo	The United States research enterprise : enhancements for the future / / Daniel S. Rosser, editor
Pubbl/distr/stampa	New York : , : Nova Publishers, , [2013] ©2013
ISBN	1-62417-917-7
Descrizione fisica	1 online resource (180 pages) : illustrations
Collana	America in the 21st century : political and economic issues
Disciplina	507.2073
Soggetti	Research - Government policy - United States Technology and state - United States
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Transformation and opportunity : the future of the U.S. research enterprise / President's Council of Advisors on Science and Technology -- Industrial competitiveness and technological advancement : debate over government policy / Wendy H. Schacht -- Cooperative R&D : federal efforts to promote industrial competitiveness / Wendy H. Schacht.

2. Record Nr.	UNINA9910788729203321
Autore	Whitehouse D. J (David J.)
Titolo	Handbook of surface and nanometrology / / David J. Whitehouse
Pubbl/distr/stampa	Boca Raton : , : CRC Press, , 2011
ISBN	0-429-14069-X 1-4200-8202-7
Edizione	[2nd ed.]
Descrizione fisica	1 online resource (982 p.)
Altri autori (Persone)	WhitehouseD. J (David J.).
Disciplina	620/.440287
Soggetti	Surfaces (Technology) - Measurement Nanostructured materials Metrology
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Rev. ed. of: Handbook of surface metrology. c1994. A Taylor & Francis book.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Front cover; Dedication; Contents; Preface; Acknowledgments; Chapter 1. Introduction-Surface and Nanometrology; Chapter 2. Characterization; Chapter 3. Processing, Operations, and Simulations; Chapter 4. Measurement Techniques; Chapter 5. Standardization-Traceability-Uncertainty; Chapter 6. Surfaces and Manufacture; Chapter 7. Surface Geometry and Its Importance in Function; Chapter 8. Surface Geometry, Scale of Size Effects, Nanometrology; Chapter 9. General Comments; Glossary; Back cover
Sommario/riassunto	David Whitehouse, known as the father of digital metrology, helped pioneer the use of nanotechnology in surface science and surface metrology, and he continues to move the field forward. In this heavily revised and expanded edition, he addresses the many paradigm shifts occurring in the field. He explains the incorporation of physics to develop optimum solutions for manufacture and performance, and provides mechanical engineers with accessible explanations of essential concepts along with the higher mathematics that is now required of those working in the field. Emphasis is placed on systems w